The SPS-2600-VAC and SPS-2800-VAC Series are MicroXact’s vacuum probe stations designed to support motorized or semi-automatic probing of up to 100mm or up to 200mm wafers in a vacuum or controlled gas atmosphere. System and precise, cost-efficient, low noise and convenient to use. These systems are built on a vibration-compensated, versatile platform capable of being configured to handle a wide range of probing applications. Ideal for icing-free testing down to 77K or for high temperature testing of devices and components that are prone to oxidation.

Features

- Available with standard repeatability/resolution (±7μm /1.5μm ) and high repeatability/resolution (better than 2μm/100nm) in X & Y.
- Z repeatability/resolution: better than 2μm/100nm
- Available with manual or motorized theta stage
- Available with 4 or 6 probe arms
- Optionally, the probe card adapter can be selected
- Microscope selection include 7:1, 12.5:1 and 16:1 digital zoom microscopes
- BNC, Triax, DC pin and RF probe arms and probes are available.
- Standard boom mount assembly for full-range XYZ positioning of microscope.
- High resolution micropositioners for micron-level positioning of probes are standard.
- Isolated, grounded, coaxial or triaxial wafer chucks are available.
- RF options available include customizable RF probes, RF bias-able chuck, and shielding enclosures.
- Thermal chuck systems for 77K to 680K testing are available.
- Software-controlled pressure control is available as an option
- The choice of roughing, or roughing/turbo pumps is available
- Automation software: XactTest™
Overview

SPS-2600-VAC and SPS-2800-VAC